



# STL20NM20N

## N-CHANNEL 200V - 0.088Ω - 20A PowerFLAT™ ULTRA LOW GATE CHARGE MDmesh™ II MOSFET

**Table 1: General Features**

TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
STL20NM20N	200 V	< 0.105 Ω	20 A

- WORLDWIDE LOWEST GATE CHARGE
- TYPICAL R<sub>DS(on)</sub> = 0.088Ω
- IMPROVED DIE-TO-FOOTPRINT RATIO
- VERY LOW PROFILE PACKAGE (1mm MAX)
- VERY LOW THERMAL RESISTANCE
- LOW GATE RESISTANCE
- LOW INPUT CAPACITANCE
- HIGH dv/dt and AVALANCHE CAPABILITIES

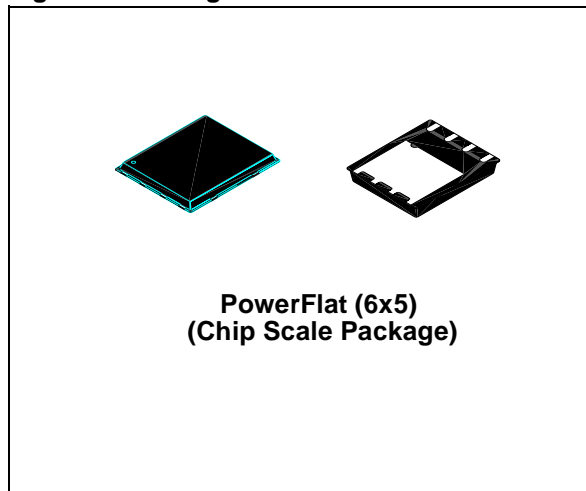
### DESCRIPTION

This 200V MOSFET with a new advanced layout brings all unique advantages of MDmesh technology to lower voltages. The device exhibits world-wide lowest gate charge for any given on-resistance. Its use is therefore ideal as primary switch in isolated DC-DC converters for Telecom and Computer applications. Used in combination with secondary-side low-voltage STripFET™ products, it contributes to reducing losses and boosting efficiency. The new PowerFLAT™ package allows a significant reduction in board space without compromising performance.

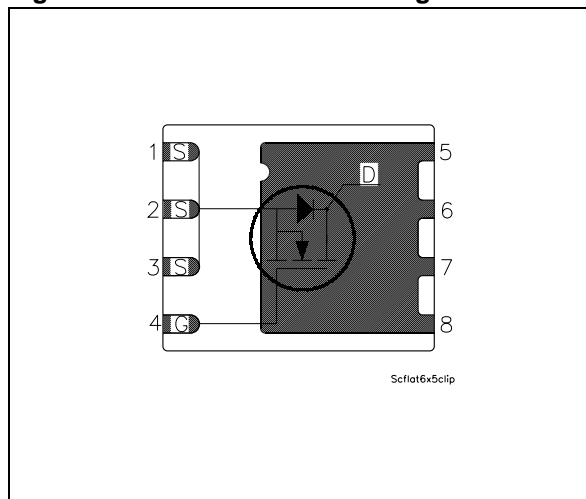
### APPLICATIONS

The MDmesh™ family is very suitable for increasing power density allowing system miniaturization and higher efficiencies

**Figure 1: Package**



**Figure 2: Internal Schematic Diagram**



**Table 2: Order Codes**

SALES TYPE	MARKING	PACKAGE	PACKAGING
STL20NM20N	L20NM20N	PowerFLAT™(6x5)	TAPE & REEL

**Table 3: Absolute Maximum ratings**

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source Voltage ( $V_{GS} = 0$ )	200	V
$V_{DGR}$	Drain-gate Voltage ( $R_{GS} = 20\text{ k}\Omega$ )	200	V
$V_{GS}$	Gate- source Voltage	$\pm 30$	V
$I_D$ (1)	Drain Current (continuous) at $T_C = 25^\circ\text{C}$ (Steady State)	20	A
	Drain Current (continuous) at $T_C = 100^\circ\text{C}$	12.3	A
$I_{DM}$ (3)	Drain Current (pulsed)	80	A
$P_{TOT}$ (2)	Total Dissipation at $T_C = 25^\circ\text{C}$ (Steady State)	2.5	W
$P_{TOT}$ (1)	Total Dissipation at $T_C = 25^\circ\text{C}$ (Steady State)	80	W
	Derating Factor (2)	0.02	W/ $^\circ\text{C}$
$dv/dt$ (4)	Peak Diode Recovery voltage slope	10	V/ns

**Table 4: Thermal Data**

Symbol	Parameter	Typ.	Max.	Unit
$R_{thj-c}$	Thermal Resistance Junction-case		1.56	$^\circ\text{C}/\text{W}$
$R_{thj-pcb}$ (2)	Thermal Resistance Junction-pcb	35	50	$^\circ\text{C}/\text{W}$
$T_j$ $T_{stg}$	Max. Operating Junction Temperature Storage Temperature	-55 to 150		$^\circ\text{C}$

**Table 5: Avalanche Characteristics**

Symbol	Parameter	Max. Value	Unit
$I_{AS}$	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by $T_j$ max)	20	A
$E_{AS}$	Single Pulse Avalanche Energy (starting $T_j = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 35\text{ V}$ )	380	mJ

**ELECTRICAL CHARACTERISTICS** ( $T_{CASE} = 25^\circ\text{C}$  UNLESS OTHERWISE SPECIFIED)**Table 6: On/Off**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source Breakdown Voltage	$I_D = 1\text{ mA}$ , $V_{GS} = 0$	200			V
$I_{DSS}$	Zero Gate Voltage Drain Current ( $V_{GS} = 0$ )	$V_{DS} = \text{Max Rating}$			1	$\mu\text{A}$
		$V_{DS} = \text{Max Rating}$ , $T_C = 125^\circ\text{C}$			10	$\mu\text{A}$
$I_{GSS}$	Gate-body Leakage Current ( $V_{DS} = 0$ )	$V_{GS} = \pm 30\text{ V}$			$\pm 100$	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250\text{ }\mu\text{A}$	3	4	5	V
$R_{DS(on)}$	Static Drain-source On Resistance	$V_{GS} = 10\text{ V}$ , $I_D = 10\text{ A}$		0.088	0.105	$\Omega$

## ELECTRICAL CHARACTERISTICS (CONTINUED)

Table 7: Dynamic

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$g_{fs}$ (5)	Forward Transconductance	$V_{DS} = 15\text{ V}$ , $I_D = 10\text{ A}$		8		S
$C_{iss}$ $C_{oss}$ $C_{rss}$	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25\text{ V}$ , $f = 1\text{ MHz}$ , $V_{GS} = 0$		800 330 130		pF pF pF
$C_{oss\text{ eq.}}$ (*)	Equivalent Output Capacitance	$V_{GS} = 0\text{ V}$ , $V_{DS} = 0\text{ V to } 160\text{ V}$		225		pF
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$	Turn-on Delay Time Rise Time Turn-off Delay Time Fall Time	$V_{DD} = 100\text{ V}$ , $I_D = 10\text{ A}$ $R_G = 4.7\Omega$ , $V_{GS} = 10\text{ V}$ (see Figure 16)		40 15 40 11		ns ns ns ns
$Q_g$ $Q_{gs}$ $Q_{gd}$	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 160\text{ V}$ , $I_D = 20\text{ A}$ , $V_{GS} = 10\text{ V}$ (see Figure 19)		32 6 25	50	nC nC nC

(\*)  $C_{oss\text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

Table 8: Source Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain Current				20	A
$I_{SDM}$ (3)	Source-drain Current (pulsed)				80	A
$V_{SD}$ (5)	Forward On Voltage	$I_{SD} = 20\text{ A}$ , $V_{GS} = 0$			1.3	V
$t_{rr}$ $Q_{rr}$ $I_{RRM}$	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 20\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ , $V_{DD} = 100\text{ V}$ , $T_j = 25^\circ\text{C}$ (see Figure 17)		160 960 128		ns nC A
$t_{rr}$ $Q_{rr}$ $I_{RRM}$	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 20\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ , $V_{DD} = 100\text{ V}$ , $T_j = 150^\circ\text{C}$ (see Figure 17)		225 1642 15		ns nC A

Note: 1. The value is rated according to  $R_{thj-c}$ .  
 2. When Mounted on FR-4 Board of  $1\text{ inch}^2$ , 2 oz Cu  
 3. Pulse width limited by safe operating area  
 4.  $I_{SD} \leq 20\text{ A}$ ,  $di/dt \leq 400\text{ A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(BR)DSS}$   
 5. Pulsed: Pulse duration =  $300\text{ }\mu\text{s}$ , duty cycle 1.5 %

Figure 3: Safe Operating Area

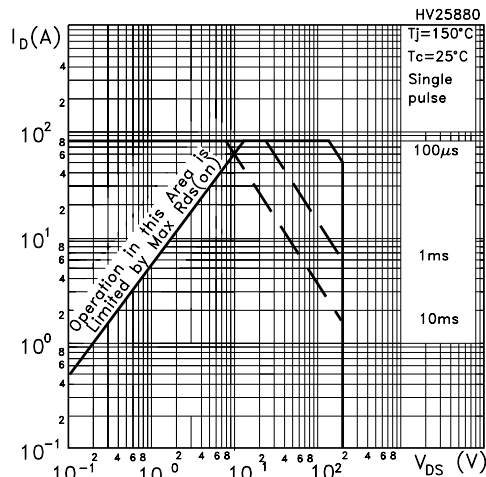


Figure 4: Output Characteristics

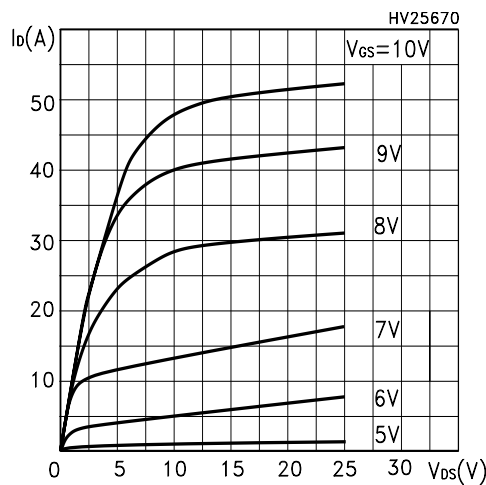


Figure 5: Transconductance

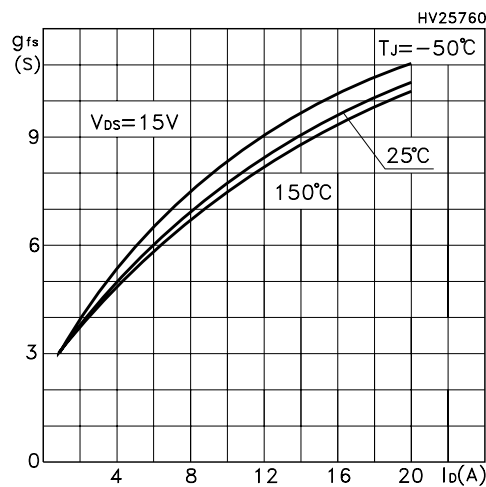


Figure 6: Thermal Impedance

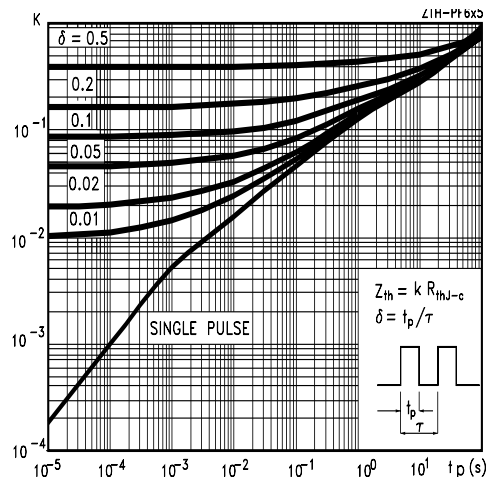


Figure 7: Transfer Characteristics

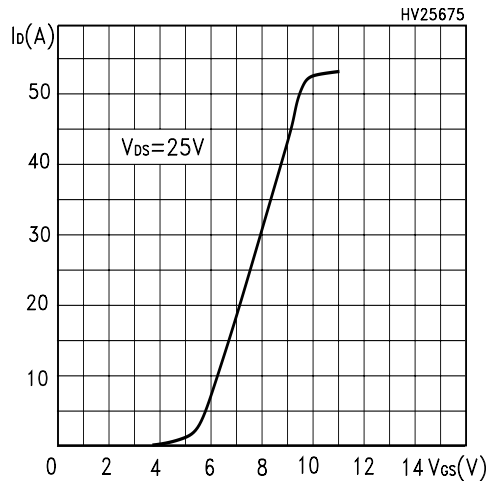


Figure 8: Static Drain-source On Resistance

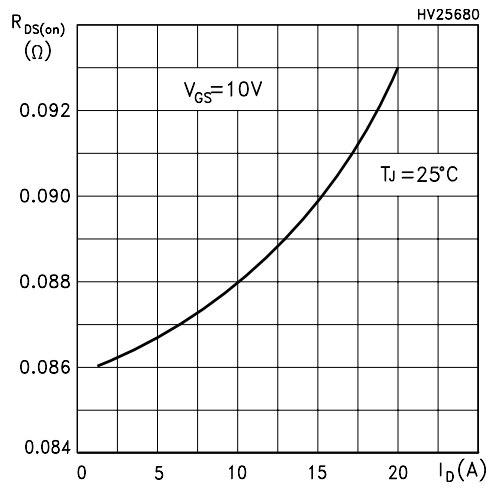


Figure 9: Gate Charge vs Gate-source Voltage

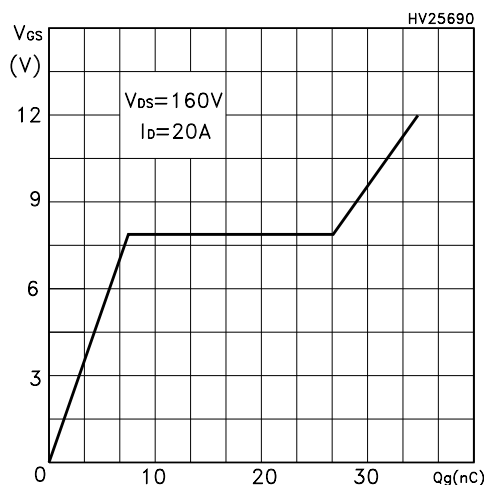


Figure 10: Normalized Gate Threshold Voltage vs Temperature

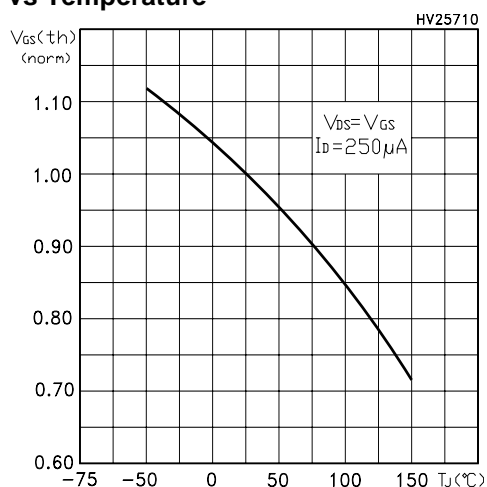


Figure 11: Source-Drain Diode Forward Characteristics

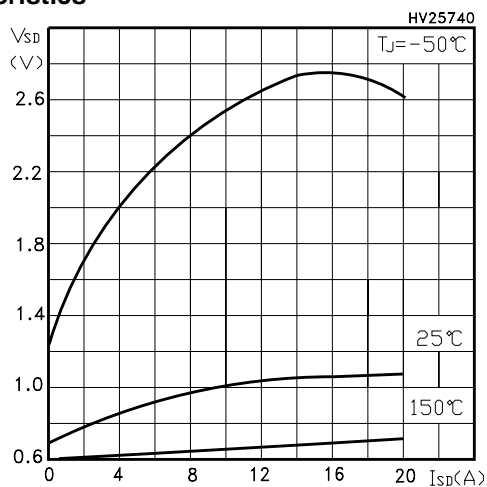


Figure 12: Capacitance Variations

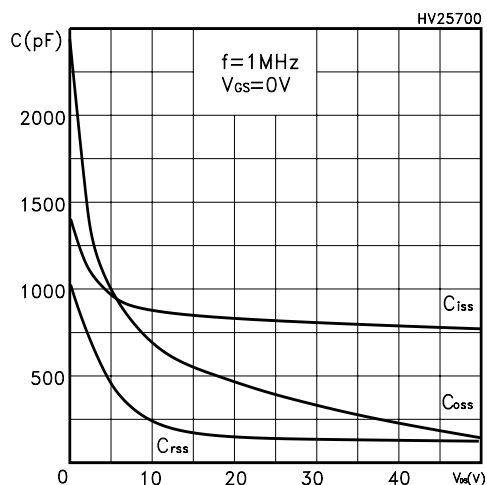


Figure 13: Normalized On Resistance vs Temperature

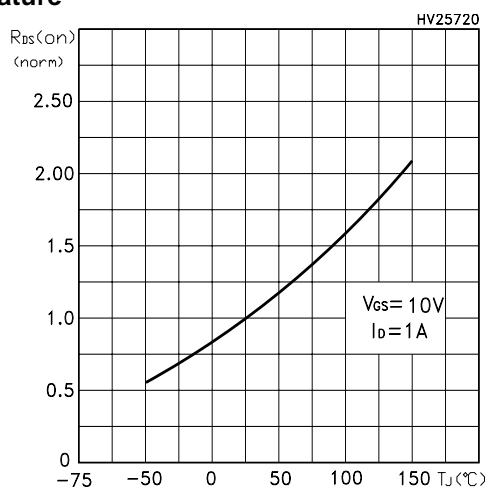
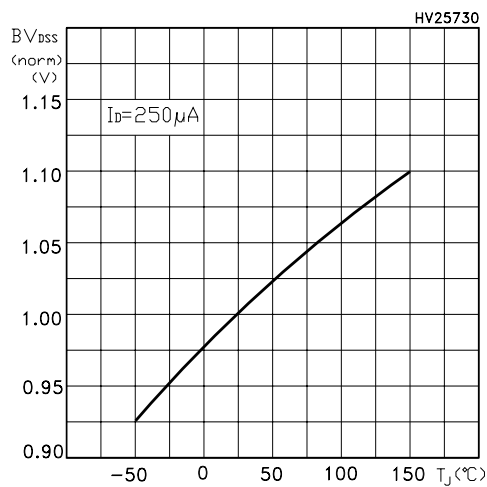
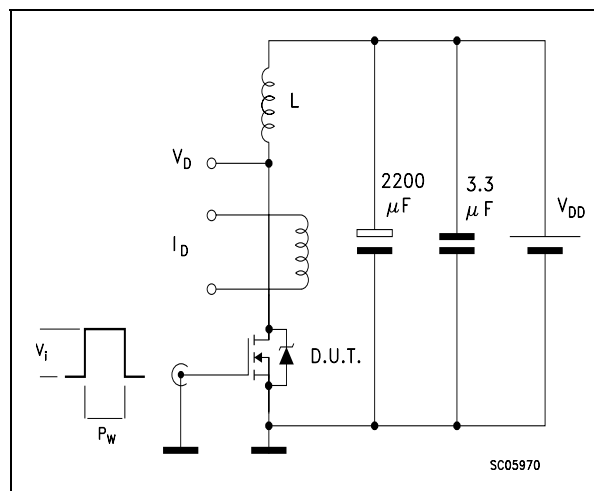


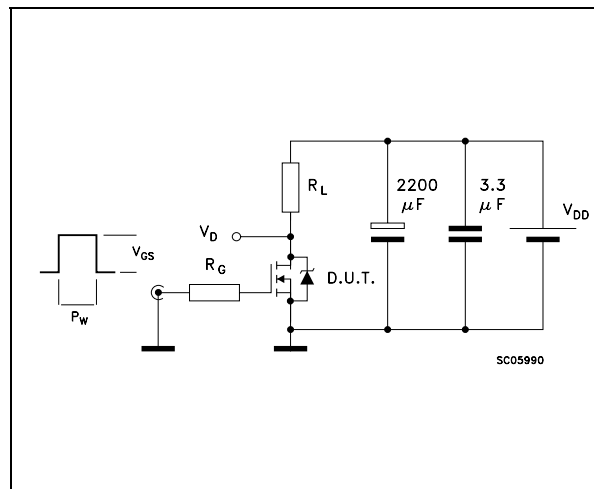
Figure 14: Normalized BVds vs Temperature



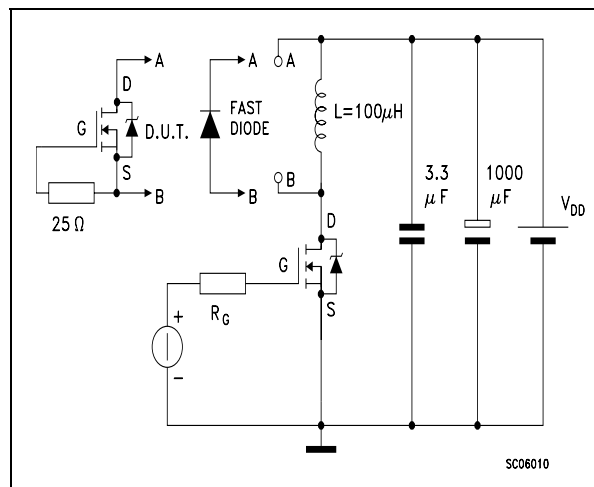
**Figure 15: Unclamped Inductive Load Test Circuit**



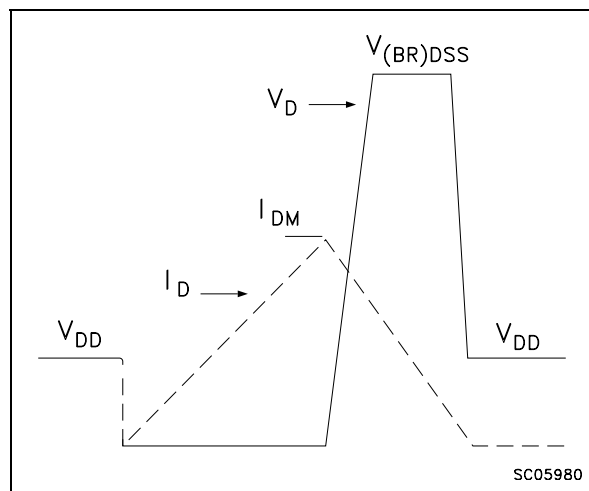
**Figure 16: Switching Times Test Circuit For Resistive Load**



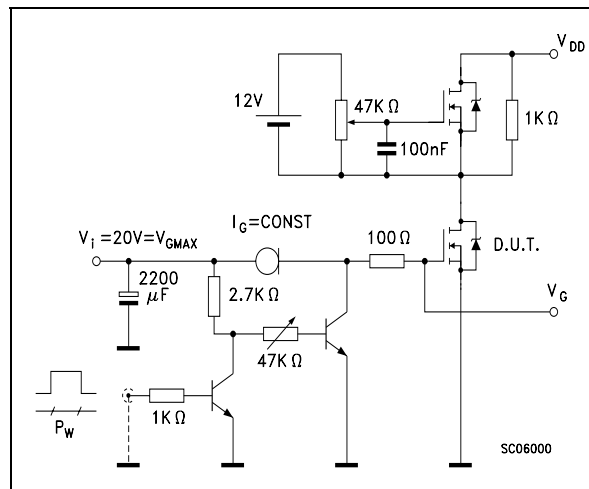
**Figure 17: Test Circuit For Inductive Load Switching and Diode Recovery Times**



**Figure 18: Unclamped Inductive Waform**

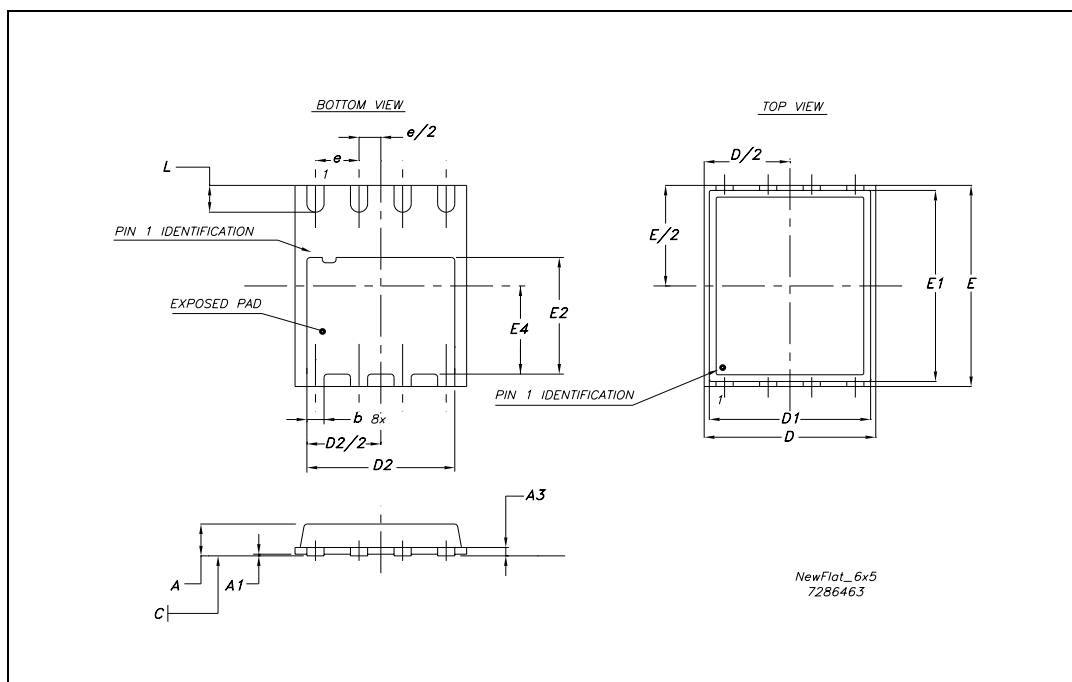


**Figure 19: Gate Charge Test Circuit**



**PowerFLAT™ (6x5) MECHANICAL DATA**

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A	0.80		0.93	0.031		0.036
A1		0.02			0.0007	0.0019
A3		0.20			0.007	
b	0.35		0.47	0.013		0.018
D		5.00			0.196	
D1		4.75			0.187	
D2	4.15		4.25	0.163		0.167
E		6.00			0.236	
E1		5.75			0.226	
E2	3.43		3.53	0.135		0.139
E4	2.85		2.68	0.101		0.105
e		1.27			0.050	
L	0.70		0.90	0.027		0.035



**Table 9: Revision History**

Date	Revision	Description of Changes
16-Feb-2005	2	New stylesheet Some Values changed on table 6 and 8
09-Jun-2005	3	Inserted curves



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